



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2858
Examiner: Not Yet Assigned

In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI
Appln. No.: 09/904,663
Filed: July 16, 2001
For: SEMICONDUCTOR DEVICE
TEST APPARATUS
Atty Ref.: KAN 120D1

**SECOND PRELIMINARY
AMENDMENT**

October 1, 2001

Commissioner for Patents
Washington, D.C. 20231

Sir:

Preliminary to examination, please amend the application as follows:

IN THE SPECIFICATION:

Please delete the paragraph on page 8, lines 17-19, and replace it with the following paragraph.

--FIG. 14A and FIG. 14B are plan views of a wafer to be measured that may be tested by the semiconductor device test apparatus illustrated in FIG. 13;-

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